Diodes Zetex Semiconductors Limited
Zetex Technology Park, Chadderton, Oldham,
OL9 9LL, United Kingdom.
Telephone No.: +44 (0)161 622 4533
Quality Dept Fax No: +44 (0)161 622 4543
E-mail:dfitton@zetex.com
Internet: http://www.zetex.com

Diodes Zetex
Semiconductors Limited
ISO/TS16949:2002
FILE NO. A9273

Date: 20/08/2008

Reliability Test Summary

RTS No: 1172

Device Family: IC Current Monitor
Package: DFN533075E, MSOP8, SM8, SO8, SOT23, SOT23-5 & TSOT23-5
Date From: 16/01/2008
Date To: 07/08/2008

Environmental Trial Data

Trial Type	Specification	Lots	Devices Tested	Devices Failed	Cumulative Hours	% Failures
CS (Cold Store)	JESD22-A119	1	45	0	45360	0.000
PCLV (Pre-conditioned Autoclave)	JESD22-A102	4	276	0	26496	0.000
PTC (Pre-conditioned Temperature Cycle Air to Air)	JESD22-A104	4	276	0	278208	0.000
PTHB (Pre-conditioned Temperature Humidity + Bias)	JESD22-A101	4	276	0	278208	0.000
RSHF (Resistance to Solder Heat Float)	JESD22-B106	2	122	0	122	0.000
Solderability (Post Hot Store)	IEC68-2-20	1	45	0	45	0.000

Electrical Stress Trials

Electrical Trial Type:	**HTOL (High Temperature Operating Life - JESD22-A108)**
Service Temperature (Deg C):	55
Ambient Temperature (Deg C):	125
Activation Energy (eV):	0.9
Confidence Level (%):	60
Actual Device Hours	200592
Equivalent Device Hours	5.417E+07
Lots	3
Devices Tested:	199
Devices Failed:	0
Mean Time To Failure (Hours):	5.912E+07
Failure Rate FITs:	16.9161
Failure Rate %/1000 Hours:	1.692E-03

David Fitton
Quality Engineer